# Hussam Amrouch

## List of Publications by Year
in descending order

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|---|---|---|---|
| 164 papers | 1,996 citations | 471371 17 h-index | 526166 27 g-index |
| 164 all docs | 164 docs citations | 164 times ranked | 823 citing authors |

| # | Article | IF | Citations |
|---|---------|-----|-----------|
| 1 | Reliability-aware design to suppress aging. , 2016, , . | | 84 |
| 2 | Negative Capacitance Transistor to Address the Fundamental Limitations in Technology Scaling: Processor Performance. IEEE Access, 2018, 6, 52754-52765. | 2.6 | 70 |
| 3 | Towards interdependencies of aging mechanisms. , 2014, , . | | 60 |
| 4 | Improving mobile gaming performance through cooperative CPU-GPU thermal management. , 2016, , . | | 54 |
| 5 | Weight-Oriented Approximation for Energy-Efficient Neural Network Inference Accelerators. IEEE Transactions on Circuits and Systems I: Regular Papers, 2020, 67, 4670-4683. | 3.5 | 54 |
| 6 | A Simulation Study of NBTI Impact on 14-nm Node FinFET Technology for Logic Applications: Device Degradation to Circuit-Level Interaction. IEEE Transactions on Electron Devices, 2019, 66, 271-278. | 1.6 | 46 |
| 7 | Ultra-low power and dependability for IoT devices (Invited paper for IoT technologies). , 2017, , . | | 44 |
| 8 | Impact of Variability on Processor Performance in Negative Capacitance FinFET Technology. IEEE Transactions on Circuits and Systems I: Regular Papers, 2020, 67, 3127-3137. | 3.5 | 44 |
| 9 | Recent advances in EM and BTI induced reliability modeling, analysis and optimization (invited). The Integration VLSI Journal, 2018, 60, 132-152. | 1.3 | 36 |
| 10 | Design Automation of Approximate Circuits With Runtime Reconfigurable Accuracy. IEEE Access, 2020, 8, 53522-53538. | 2.6 | 36 |
| 11 | Towards Aging-Induced Approximations. , 2017, , . | | 35 |
| 12 | Impact of Extrinsic Variation Sources on the Device-to-Device Variation in Ferroelectric FET. , 2020, , . | | 35 |
| 13 | Reliability in Super- and Near-Threshold Computing: A Unified Model of RTN, BTI, and PV. IEEE Transactions on Circuits and Systems I: Regular Papers, 2018, 65, 293-306. | 3.5 | 33 |
| 14 | Impact of Interface Traps on Negative Capacitance Transistor: Device and Circuit Reliability. IEEE Journal of the Electron Devices Society, 2020, 8, 1193-1201. | 1.2 | 33 |
| 15 | NPU Thermal Management. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 2020, 39, 3842-3855. | 1.9 | 31 |
| 16 | Temperature Dependence and Temperature-Aware Sensing in Ferroelectric FET. , 2020, , . | | 31 |
| 17 | Aging-Aware Voltage Scaling. , 2016, , . | | 31 |
| 18 | Unveiling the Impact of IR-Drop on Performance Gain in NCFET-Based Processors. IEEE Transactions on Electron Devices, 2019, 66, 3215-3223. | 1.6 | 30 |

| # | Article | IF | Citations |
|---|---------|-----|-----------|
| 19 | A Cross-Layer Gate-Level-to-Application Co-Simulation for Design Space Exploration of Approximate Circuits in HEVC Video Encoders. IEEE Transactions on Circuits and Systems for Video Technology, 2020, 30, 3814-3828. | 5.6 | 29 |
| 20 | Stress balancing to mitigate NBTI effects in register files. , 2013, , . | | 27 |
| 21 | Impact of BTI on dynamic and static power: From the physical to circuit level. , 2017, , . | | 26 |
| 22 | On the Channel Percolation in Ferroelectric FET Towards Proper Analog States Engineering. , 2021, , . | | 26 |
| 23 | Device to Circuit Framework for Activity-Dependent NBTI Aging in Digital Circuits. IEEE Transactions on Electron Devices, 2019, 66, 316-323. | 1.6 | 25 |
| 24 | Designing guardbands for instantaneous aging effects. , 2016, , . | | 24 |
| 25 | Performance, Power and Cooling Trade-Offs with NCFET-based Many-Cores. , 2019, , . | | 23 |
| 26 | Lucid infrared thermography of thermally-constrained processors. , 2015, , . | | 22 |
| 27 | Approximate Computing for ML. , 2021, , . | | 22 |
| 28 | MLCAD: A Survey of Research in Machine Learning for CAD Keynote Paper. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 2022, 41, 3162-3181. | 1.9 | 22 |
| 29 | Brain-Inspired Computing for Wafer Map Defect Pattern Classification. , 2021, , . | | 21 |
| 30 | On the Efficiency of Voltage Overscaling under Temperature and Aging Effects. IEEE Transactions on Computers, 2019, 68, 1647-1662. | 2.4 | 19 |
| 31 | Hardware Trojan Detection Using Controlled Circuit Aging. IEEE Access, 2020, 8, 77415-77434. | 2.6 | 19 |
| 32 | Self-Immunity Technique to Improve Register File Integrity Against Soft Errors. , 2011, , . | | 18 |
| 33 | Connecting the physical and application level towards grasping aging effects. , 2015, , . | | 18 |
| 34 | Aging-Aware Boosting. IEEE Transactions on Computers, 2018, 67, 1217-1230. | 2.4 | 18 |
| 35 | Machine Learning for On-the-Fly Reliability-Aware Cell Library Characterization. IEEE Transactions on Circuits and Systems I: Regular Papers, 2021, 68, 2569-2579. | 3.5 | 18 |
| 36 | Thermal management for dependable on-chip systems. , 2013, , . | | 17 |

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|---|---------|-----|-----------|
| 37 | Emerging (un-)reliability based security threats and mitigations for embedded systems. , 2017, , . | | 17 |
| 38 | Energy Efficient Edge Computing Enabled by Satisfaction Games and Approximate Computing. IEEE Transactions on Green Communications and Networking, 2022, 6, 281-294. | 3.5 | 17 |
| 39 | On the Resiliency of NCFET Circuits Against Voltage Over-Scaling. IEEE Transactions on Circuits and Systems I: Regular Papers, 2021, 68, 1481-1492. | 3.5 | 16 |
| 40 | Control Variate Approximation for DNN Accelerators. , 2021, , . | | 16 |
| 41 | Modeling and Mitigating Time-Dependent Variability From the Physical Level to the Circuit Level. IEEE Transactions on Circuits and Systems I: Regular Papers, 2019, 66, 2671-2684. | 3.5 | 15 |
| 42 | Towards a New Thermal Monitoring Based Framework for Embedded CPS Device Security. IEEE Transactions on Dependable and Secure Computing, 2022, 19, 524-536. | 3.7 | 15 |
| 43 | Machine Learning Based Online Full-Chip Heatmap Estimation. , 2020, , . | | 15 |
| 44 | On the Reliability of FeFET On-Chip Memory. IEEE Transactions on Computers, 2022, 71, 947-958. | 2.4 | 15 |
| 45 | Impact of Self-Heating on Negative-Capacitance FinFET: Device-Circuit Interaction. IEEE Transactions on Electron Devices, 2021, 68, 1420-1424. | 1.6 | 15 |
| 46 | On the Reliability of In-Memory Computing: Impact of Temperature on Ferroelectric TCAM. , 2021, , . | | 15 |
| 47 | Trading Off Temperature Guardbands via Adaptive Approximations. , 2018, , . | | 14 |
| 48 | NCFET-Aware Voltage Scaling. , 2019, , . | | 14 |
| 49 | New Worst-Case Timing for Standard Cells Under Aging Effects. IEEE Transactions on Device and Materials Reliability, 2019, 19, 149-158. | 1.5 | 14 |
| 50 | Optimizing temperature guardbands. , 2017, , . | | 13 |
| 51 | Interdependencies of Degradation Effects and Their Impact on Computing. IEEE Design and Test, 2017, 34, 59-67. | 1.1 | 13 |
| 52 | Estimating and Mitigating Aging Effects in Routing Network of FPGAs. IEEE Transactions on Very Large Scale Integration (VLSI) Systems, 2019, 27, 651-664. | 2.1 | 13 |
| 53 | Performance Optimization of Analog Circuits in Negative Capacitance Transistor Technology. Microelectronics Journal, 2021, 115, 105193. | 1.1 | 13 |
| 54 | Modeling emerging technologies using machine learning. , 2020, , . | | 13 |

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|---|---------|-----|-----------|
| 55 | Scalable Machine Learning to Estimate the Impact of Aging on Circuits Under Workload Dependency. IEEE Transactions on Circuits and Systems I: Regular Papers, 2022, 69, 2142-2155. | 3.5 | 13 |
| 56 | Brain-Inspired Computing for Circuit Reliability Characterization. IEEE Transactions on Computers, 2022, , 1-1. | 2.4 | 13 |
| 57 | COOL. , 2012, , . | | 12 |
| 58 | Analyzing the thermal hotspots in FPGA-based embedded systems. , 2013, , . | | 12 |
| 59 | Reliability Challenges with Self-Heating and Aging in FinFET Technology. , 2019, , . | | 12 |
| 60 | Modeling the Interdependences Between Voltage Fluctuation and BTI Aging. IEEE Transactions on Very Large Scale Integration (VLSI) Systems, 2019, 27, 1652-1665. | 2.1 | 12 |
| 61 | BTI and HCD Degradation in a Complete 32 Ã— 64 bit SRAM Array â€" including Sense Amplifiers and Write Drivers â€" under Processor Activity. , 2020, , . | | 12 |
| 62 | Transistor Self-Heating: The Rising Challenge for Semiconductor Testing. , 2021, , . | | 12 |
| 63 | On-Demand Mobile CPU Cooling With Thin-Film Thermoelectric Array. IEEE Micro, 2021, 41, 67-73. | 1.8 | 12 |
| 64 | All-in-Memory Brain-Inspired Computing Using FeFET Synapses. Frontiers in Electronics, 2022, 3, . | 2.0 | 12 |
| 65 | Traps Based Reliability Barrier on Performance and Revealing Early Ageing in Negative Capacitance FET. , 2021, , . | | 11 |
| 66 | Positive/Negative Approximate Multipliers for DNN Accelerators. , 2021, , . | | 11 |
| 67 | Hot Spot Identification and System Parameterized Thermal Modeling for Multi-Core Processors Through Infrared Thermal Imaging. , 2019, , . | | 10 |
| 68 | Aging Compensation With Dynamic Computation Approximation. IEEE Transactions on Circuits and Systems I: Regular Papers, 2020, 67, 1319-1332. | 3.5 | 10 |
| 69 | Post-Silicon Heat-Source Identification and Machine-Learning-Based Thermal Modeling Using Infrared Thermal Imaging. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 2021, 40, 694-707. | 1.9 | 10 |
| 70 | FeFET-Based Binarized Neural Networks Under Temperature-Dependent Bit Errors. IEEE Transactions on Computers, 2022, 71, 1681-1695. | 2.4 | 10 |
| 71 | Real-Time Full-Chip Thermal Tracking: A Post-Silicon, Machine Learning Perspective. IEEE Transactions on Computers, 2021, , 1-1. | 2.4 | 10 |
| 72 | On the Workload Dependence of Self-Heating in FinFET Circuits. IEEE Transactions on Circuits and Systems II: Express Briefs, 2020, 67, 1949-1953. | 2.2 | 9 |

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| 73 | Exposing Hardware Trojans in Embedded Platforms via Short-Term Aging. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 2020, 39, 3519-3530. | 1.9 | 9 |
| 74 | NCFET to Rescue Technology Scaling: Opportunities and Challenges. , 2020, , . | | 9 |
| 75 | Longevity of Commodity DRAMs in Harsh Environments Through Thermoelectric Cooling. IEEE Access, 2021, 9, 83950-83962. | 2.6 | 9 |
| 76 | Cell library characterization using machine learning for design technology co-optimization. , 2020, , . | | 9 |
| 77 | Rebirth-FTL: Lifetime optimization via Approximate Storage for NAND Flash. , 2019, , . | | 8 |
| 78 | Reliability-Aware Quantization for Anti-Aging NPUs. , 2021, , . | | 8 |
| 79 | FN-CACTI: Advanced CACTI for FinFET and NC-FinFET Technologies. IEEE Transactions on Very Large Scale Integration (VLSI) Systems, 2022, 30, 339-352. | 2.1 | 8 |
| 80 | Software-Managed Read and Write Wear-Leveling for Non-Volatile Main Memory. Transactions on Embedded Computing Systems, 2022, 21, 1-24. | 2.1 | 8 |
| 81 | Reliable Binarized Neural Networks on Unreliable Beyond Von-Neumann Architecture. IEEE Transactions on Circuits and Systems I: Regular Papers, 2022, 69, 2516-2528. | 3.5 | 8 |
| 82 | ICCAD Tutorial Session Paper Ferroelectric FET Technology and Applications: From Devices to Systems. , 2021, , . | | 8 |
| 83 | Accurate Thermal-Profile Estimation and Validation for FPGA-Mapped Circuits. , 2013, , . | | 7 |
| 84 | Voltage Adaptation Under Temperature Variation. , 2018, , . | | 7 |
| 85 | Impact of Radiation on Negative Capacitance FinFET. , 2020, , . | | 7 |
| 86 | Power-Efficient Heterogeneous Many-Core Design With NCFET Technology. IEEE Transactions on Computers, 2021, 70, 1484-1497. | 2.4 | 7 |
| 87 | Minimizing Excess Timing Guard Banding Under Transistor Self-Heating Through Biasing at Zero-Temperature Coefficient. IEEE Access, 2021, 9, 30687-30697. | 2.6 | 7 |
| 88 | Estimating and optimizing BTI aging effects. , 2018, , . | | 6 |
| 89 | Weighted time lag plot defect parameter extraction and GPU-based BTI modeling for BTI variability. , 2018, , . | | 6 |
| 90 | Power Side-Channel Attacks in Negative Capacitance Transistor. IEEE Micro, 2020, 40, 74-84. | 1.8 | 6 |

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| 91 | Impact of Interface Traps Induced Degradation on Negative Capacitance FinFET. , 2020, , . | | 6 |
| 92 | Dynamic Power and Energy Management for NCFET-Based Processors. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 2020, 39, 3361-3372. | 1.9 | 6 |
| 93 | Impact of NBTI Aging on Self-Heating in Nanowire FET. , 2020, , . | | 6 |
| 94 | Bridging the Gap Between Voltage Over-Scaling and Joint Hardware Accelerator-Algorithm Closed-Loop. IEEE Transactions on Circuits and Systems for Video Technology, 2022, 32, 398-410. | 5.6 | 6 |
| 95 | On the Critical Role of Ferroelectric Thickness for Negative Capacitance Device-Circuit Interaction. IEEE Journal of the Electron Devices Society, 2021, 9, 1262-1268. | 1.2 | 6 |
| 96 | Special Session: Machine Learning for Semiconductor Test and Reliability. , 2021, , . | | 6 |
| 97 | Machine Learning for Circuit Aging Estimation under Workload Dependency. , 2021, , . | | 6 |
| 98 | Binarized SNNs: Efficient and Error-Resilient Spiking Neural Networks through Binarization. , 2021, , . | | 6 |
| 99 | Cleaved-Gate Ferroelectric FET for Reliable Multi-Level Cell Storage. , 2022, , . | | 6 |
| 100 | Power and thermal management in massive multicore chips. , 2016, , . | | 5 |
| 101 | Reliability Estimations of Large Circuits in Massively-Parallel GPU-SPICE. , 2018, , . | | 5 |
| 102 | Dynamic Guardband Selection: Thermal-Aware Optimization for Unreliable Multi-Core Systems. IEEE Transactions on Computers, 2019, 68, 53-66. | 2.4 | 5 |
| 103 | Massively Parallel Circuit Setup in GPU-SPICE. IEEE Transactions on Computers, 2023, 72, 2127-2138. | 2.4 | 5 |
| 104 | A Framework for Crossing Temperature-Induced Timing Errors Underlying Hardware Accelerators to the Algorithm and Application Layers. IEEE Transactions on Computers, 2022, 71, 349-363. | 2.4 | 5 |
| 105 | Full-Chip Power Density and Thermal Map Characterization for Commercial Microprocessors Under Heat Sink Cooling. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 2022, 41, 1453-1466. | 1.9 | 5 |
| 106 | Robust Brain-Inspired Computing: On the Reliability of Spiking Neural Network Using Emerging Non-Volatile Synapses. , 2021, , . | | 5 |
| 107 | Towards NN-based Online Estimation of the Full-Chip Temperature and the Rate of Temperature Change. , 2020, , . | | 5 |
| 108 | Variability Effects in FinFET Transistors and Emerging NC-FinFET. , 2021, , . | | 5 |

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| 109 | Thermal-Aware Design for Approximate DNN Accelerators. IEEE Transactions on Computers, 2022, 71, 2687-2697. | 2.4 | 5 |
| 110 | hevcDTM: Application-driven Dynamic Thermal Management for High Efficiency Video Coding. , 2014, , . | | 4 |
| 111 | RESI: Register-Embedded Self-Immunity for Reliability Enhancement. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 2014, 33, 677-690. | 1.9 | 4 |
| 112 | Dynamic resource management for heterogeneous many-cores. , 2018, , . | | 4 |
| 113 | Aging Gracefully with Approximation. , 2019, , . | | 4 |
| 114 | Selecting the Optimal Energy Point in Near-Threshold Computing. , 2019, , . | | 4 |
| 115 | Impact of Self-Heating on Performance, Power and Reliability in FinFET Technology. , 2020, , . | | 4 |
| 116 | Impact of NCFET Technology on Eliminating the Cooling Cost and Boosting the Efficiency of Google TPU. IEEE Transactions on Computers, 2022, 71, 906-918. | 2.4 | 4 |
| 117 | mDTM: Multi-objective dynamic thermal management for on-chip systems. , 2014, , . | | 4 |
| 118 | Trojan Detection in Embedded Systems With FinFET Technology. IEEE Transactions on Computers, 2022, 71, 3061-3071. | 2.4 | 4 |
| 119 | Modeling TPU Thermal Maps Under Superlattice Thermoelectric Cooling. IEEE Access, 2022, 10, 21970-21978. | 2.6 | 4 |
| 120 | Reliability degradation in the scope of aging â€" From physical to system level. , 2015, , . | | 3 |
| 121 | Stress-aware routing to mitigate aging effects in SRAM-based FPGAs. , 2016, , . | | 3 |
| 122 | Containing guardbands. , 2017, , . | | 3 |
| 123 | Machine Learning Techniques to Support Many-Core Resource Management: Challenges and Opportunities. , 2019, , . | | 3 |
| 124 | Automated Design Approximation to Overcome Circuit Aging. IEEE Transactions on Circuits and Systems I: Regular Papers, 2021, 68, 4710-4721. | 3.5 | 3 |
| 125 | Impact of Negative Capacitance Field-Effect Transistor (NCFET) on Many-Core Systems. , 2021, , 107-123. | | 3 |
| 126 | Towards Reliable In-Memory Computing:From Emerging Devices to Post-von-Neumann Architectures. , 2021, , . | | 3 |

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| 127 | Security Closure of Physical Layouts ICCAD Special Session Paper. , 2021, , . | | 3 |
| 128 | Toward Security Closure in the Face of Reliability Effects ICCAD Special Session Paper. , 2021, , . | | 3 |
| 129 | On Extracting Reliability Information from Speed Binning. , 2022, , . | | 3 |
| 130 | Aging-constrained performance optimization for multi cores. , 2018, , . | | 2 |
| 131 | Aging Effects: From Physics to CAD. , 2019, , 43-69. | | 2 |
| 132 | Energy Optimization in NCFET-based Processors. , 2020, , . | | 2 |
| 133 | Characterizing the Thermal Feasibility of Monolithic 3D Microprocessors. IEEE Access, 2021, 9, 120715-120729. | 2.6 | 2 |
| 134 | On the Critical Role of Ferroelectric Thickness for Negative Capacitance Transistor Optimization. , 2021, , . | | 2 |
| 135 | Reliability-Driven Voltage Optimization for NCFET-based SRAM Memory Banks. , 2021, , . | | 2 |
| 136 | Soft Errors in Negative Capacitance FDSOI SRAMs. , 2021, , . | | 2 |
| 137 | PROTON: Post-Synthesis Ferroelectric Thickness Optimization for NCFET Circuits. IEEE Transactions on Circuits and Systems I: Regular Papers, 2021, 68, 4299-4309. | 3.5 | 2 |
| 138 | Cross-layer Design for Computing-in-Memory. , 2021, , . | | 2 |
| 139 | On the Resiliency of NC-FinFET SRAMs against Variation: MFIS Structure. , 2021, , . | | 2 |
| 140 | Design Close to the Edge for Advanced Technology using Machine Learning and Brain-Inspired Algorithms. , 2022, , . | | 2 |
| 141 | Ferroelectric FET Threshold Voltage Optimization for Reliable In-Memory Computing. , 2022, , . | | 2 |
| 142 | Machine Learning-Based Microarchitecture- Level Power Modeling of CPUs. IEEE Transactions on Computers, 2023, 72, 941-956. | 2.4 | 2 |
| 143 | HW/SW Codesign for Approximate In-Memory Computing. , 2022, , . | | 2 |
| 144 | Designing reliable, yet energy-efficient guardbands. , 2016, , . | | 1 |

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|---|---------|-----|-----------|
| 145 | Evaluating and mitigating degradation effects in multimedia circuits. , 2017, , . | | 1 |
| 146 | The Vital Role of Machine Learning in Developing Emerging Technologies. , 2021, , 29-57. | | 1 |
| 147 | Self-Heating Effects from Transistors to Gates. , 2021, , . | | 1 |
| 148 | Impact of NCFET on Neural Network Accelerators. IEEE Access, 2021, 9, 43748-43758. | 2.6 | 1 |
| 149 | Electrothermal Simulation and Optimal Design of Thermoelectric Cooler Using Analytical Approach. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 2022, 41, 3066-3077. | 1.9 | 1 |
| 150 | Run-Time Accuracy Reconfigurable Stochastic Computing for Dynamic Reliability and Power Management: Work-in-Progress. , 2020, , . | | 1 |
| 151 | Design-time exploration of voltage switching against power analysis attacks in 14Ânm FinFET technology. The Integration VLSI Journal, 2022, 85, 27-34. | 1.3 | 1 |
| 152 | Brain-Inspired Computing: Adventure from Beyond CMOS Technologies to Beyond von Neumann Architectures ICCAD Special Session Paper. , 2021, , . | | 1 |
| 153 | Variability-Aware Approximate Circuit Synthesis via Genetic Optimization. IEEE Transactions on Circuits and Systems I: Regular Papers, 2022, 69, 4141-4153. | 3.5 | 1 |
| 154 | Hardware and software innovations in energy-efficient system-reliability monitoring. , 2017, , . | | 0 |
| 155 | Impact of NBTI on Increasing the Susceptibility of FinFET to Radiation. , 2019, , . | | 0 |
| 156 | Stack Usage Analysis for Efficient Wear Leveling in Non-Volatile Main Memory Systems. , 2019, , . | | 0 |
| 157 | The Impact of Emerging Technologies on Architectures and System-level Management: Invited Paper. , 2019, , . | | 0 |
| 158 | Modeling and Evaluating the Gate Length Dependence of BTI. IEEE Transactions on Circuits and Systems II: Express Briefs, 2019, 66, 1527-1531. | 2.2 | 0 |
| 159 | FeFET and NCFET for Future Neural Networks: Visions and Opportunities. , 2021, , . | | 0 |
| 160 | Session details: Session 6B: Testing, Reliability, Fault-Tolerance. , 2021, , . | | 0 |
| 161 | On the Effectiveness of Quantization and Pruning on the Performance of FPGAs-based NN Temperature Estimation. , 2021, , . | | 0 |
| 162 | Thermal Management and Communication Virtualization for Reliability Optimization in MPSoCs. Embedded Systems, 2021, , 181-205. | 0.6 | 0 |

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|---|---------|----|-----------|
| 163 | Session details: Session 5: ML for Systems. , 2020, , . | | 0 |
| 164 | Session details: Session 1: DNN for CAD. , 2020, , . | | 0 |